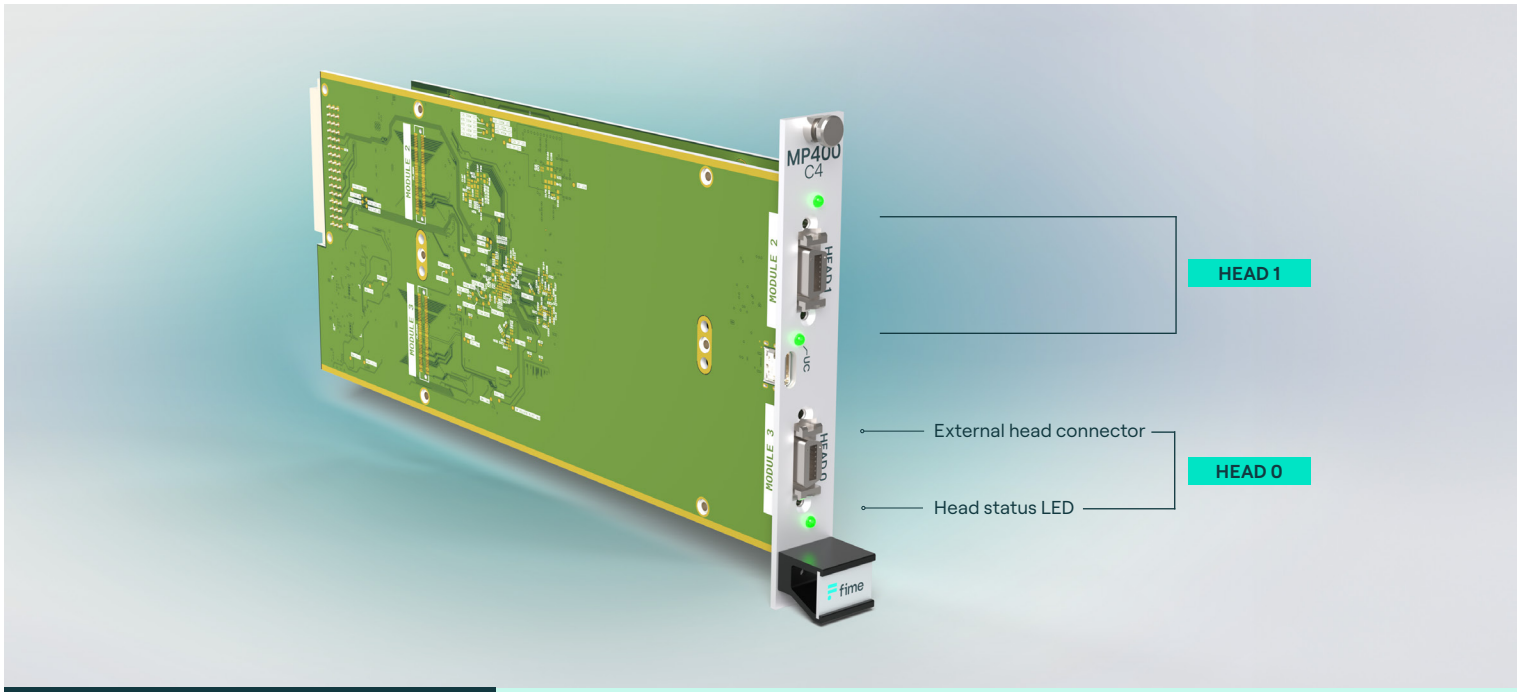
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Datasheet

# MP400 C4

## A multiprotocol production tester for contact technology

Smartcards, micromodules and secure elements




### New design

- New hardware architecture
- Based on powerful CPU ARM Dual-Core & FPGA
- GigaBit Ethernet
- OS Embedded Linux
- 2 test heads per tester

### Supported protocols

- ISO 7816
- SWP/HCI
- I2C & I3C
- SPI

### Application domains

- Personalization
- Pre-personalization
- OS loading
- Electrical testing

### Business areas

- Telecom
- Banking
- E-health
- M2M
- U-SIM
- Micro-module production
- NFC

### Supported tests

- Open Short
- Leakage current
- Chip consumption
- Current & voltage measurement
- Parametric tests
- Timing measurement

### Use cases

- Production line testing
- Personalization verification
- Micromodule quality control
- Module sensitivity assessement

| Specifications | |
|---|---|
| **General** | |
| NFC Simulation | Terminal emulation only |
| Testers | 2 test heads |
| Rack | Compatible with rack x1, x4, x8, x16 |
| **Analog settings** | |
| Voltage, frequency, pin states | |
| **Protocol settings** | |
| ETU width, guard time, waiting times, data-rates | |
| **Electrical tests** | |
| Open/Short test (all contacts) | |
| Leakage current measurement (all contacts) | |
| Voltage measurements (all contacts, static & dynamic modes) | |
| Current measurements (all contacts, static & dynamic modes) | |
| V Force /I Force for parametric tests | |
| Anti tearing tests | |
| SWP Specific function measurement | |
| Concurrent I/O testing | |
| **Supported protocols** | |
| **ISO/IEC 7816-3** | |
| T=0 and T= 1 protocols | |
| Support of Class A, B, C & D | |
| **SWP (ETSI TS 102613 & TS 102622)** | |
| SWP transmission (assisted by hardware) | |
| LLC layers support (ACT, CLT, SHDLC by firmware) | |
| **I2C & I3C** | |
| 7-bit & 10-bit addressing | |
| Standard & Fast mode | |
| Clock Stretching | |
| **SPI** | |
| SPI x1 lane | |
| Polarity & Edge Clock programmable | |
| 8-bit data width | |

## Key features

**Scalable, compatible design**

- **Modular architecture**: up to **32 test heads** per rack
- **Rack compatibility**: works with new **MP400** racks and **MP300** racks

**Full-feature performance**

- Multiprotocol support
- Fully programmable parameters
- Advanced measurements

**Application development**

- Externally running application
- Support of embedded application
- Multiprocessing
- Toolchain for cross-compilation provided

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## Contact

**To learn more about how Fime can help your business:**
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F-D-MP400C4-AA
**A multiprotocol production tester for contact technology.**

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